

Recent Developments of Miniaturised Microwave Induced Plasma Sources - Modelling and Applications -



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Introduction

Microwave induced plasma (MIP) sources have found applications in atomic spectrometry for several decades. Many efforts have been made to understand the physical processes in these types of discharges and to optimise the existing devices towards robustness and stability for analytical applications.

However, these sources are constructed of rigid high frequency elements, such as cavities, matching elements etc., requiring a certain device depending minimum size.

Recently, we developed an MIP source which is completely constructed in microstrip technology. This enables small set-ups which in turn allow for low power and gas consumption. Common microchip production processes for the formation of quasi two-dimensional structures are applicable for an inexpensive and easy production of these devices. These MIPs are intrinsically suitable as a part of a miniaturised Total Analysis System (μ TAS) because of their design and production.

In the following we present different designs of our **MicroStrip Plasma (MSP)** Source optimised for different applications as Optical Emission Spectrometry (OES) and Atomic Absorption Spectrometry (AAS) for atmospheric and low pressure discharges in Ar and He.

Outlook

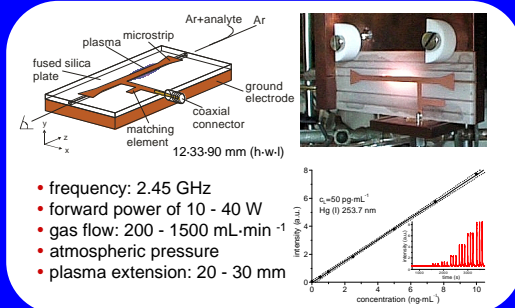
MIPs based on microstrip technology are of high potential for μ TAS applications as shown by the MSP. Now designs are already available for discharges in Ar and He at atmospheric and low pressure for OES and AAS applications. Working conditions range from power levels of a few W up to 40 W and gas flows from some 10 mL \cdot min⁻¹ up to 1500 mL \cdot min⁻¹. Improvements of wafer materials and electrode designs led to smaller dimensions and lower power consumption.

Further research should focus on the integration and miniaturisation of the supplementary and evaluation devices as:

- Very small (\sim cm²) microwave semiconductor generators with frequency sweep using appropriate ICs already available for mobile phones.
- Integrated optical components for radiation collection.
- Use of small scale spectrometers.
- Sample introductions systems on chip.

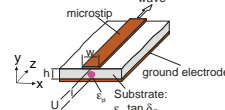
...and an advanced MSP production process like wet etching and gluing techniques.

MSP I for OES: Hg by Cold Vapour Technique



MSP Modelling

Electric field in the quasi static approximation



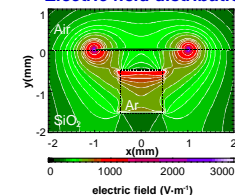
- electric field from scalar potential
- $\nabla \cdot \epsilon \nabla j = 0 \quad \vec{E} = -\nabla j$
(TEM-approximation)
- characteristic impedance

- $Z = \frac{1}{c_0} \sqrt{C_{\text{substr}}^* C_{\text{air}}^*}$
- equivalent voltage
- $U = \sqrt{2 P Z_c}$

Modelling gives impact to:

- electrode design
- compensated edge
- substrate material (ϵ_r)
- electrode separation gap
- channel shape

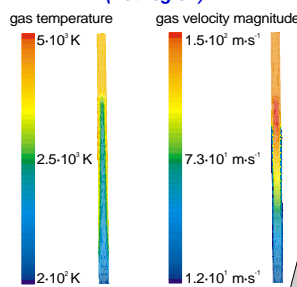
Electric field distribution



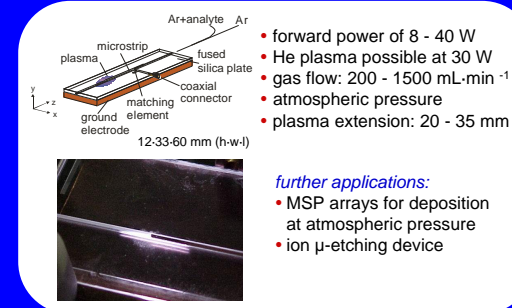
Electric field for a potential difference of 1V. Actual field values follow from equivalent voltage.

Fluid simulations in MSP channel

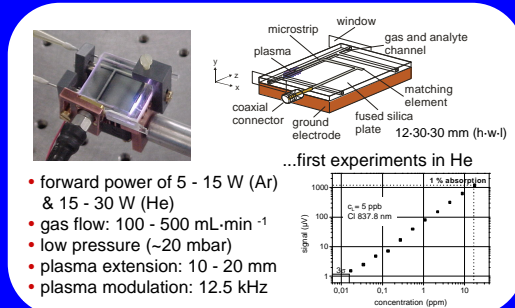
(hot region)



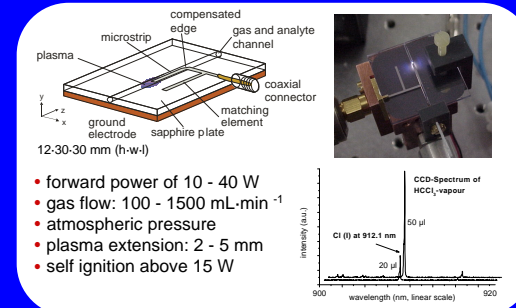
MSP II : Optimised Setup for OES



MSP III: Cl by Laser Diode AAS



MSP IV : Helium Plasma for OES



[1] U. Engel, A.M. Bilgiç, O. Haase, E. Voges, J.A.C. Broekaert, A Microwave-Induced Plasma Based on Microstrip Technology and Its Use for the Atomic Emission Spectrometric Determination of Mercury with the Aid of the Cold-Vapour Technique, *Anal. Chem.*, **72** (1), 193 - 197 (2000).

[2] A.M. Bilgiç, U. Engel, E. Voges, M. Kückelheim, J.A.C. Broekaert, A New Low Power Microwave Plasma Source using Microstrip Technology for Atomic Emission Spectrometry, *Plasma Sources Sci. Technol.*, in print (1999).